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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,080	JANG ET AL.	
Examiner	Art Unit	
Juan A. Torres	2611	

	SEARCHED			
Class	Subclass	Date	Examiner	
375	346, 287	1/23/2007	JATM	
455	296	1/23/2007	JATM	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH N (INCLUDING SEARC)
	DATE	EXMR
EAST	1/23/2007	JATM
IDS Flag clearance	1/23/2007	JATM
Invenor search	1/23/2007	JATM
Claim interference search	1/23/2007	JATM
Google	1/23/2007	JATM
Scirus	1/23/2007	JATM
IEEE	1/23/2007	JATM